

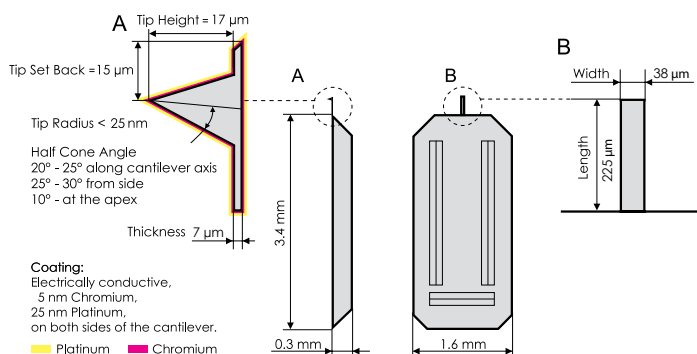


AFM probe Model: *ElectriTap190-G*



This probe has alignment grooves on the backside of the holder chip.

- Tapping, Intermittent Contact and Electric Modes like:
 - Scanning Capacitance Microscopy (SCM)
 - Electrostatic Force Microscopy (EFM)
 - Kelvin probe Force Microscopy (KFM)
 - Scanning probe lithography
- Rotated Monolithic Silicon Probe
- Symmetric Tip Shape
- Chipsize: 3.4 x 1.6 x 0.3 mm
- Alignment Grooves
- Long Cantlever
- Coating: Electrically conductive coating of 5 nm Chromium and 25 nm Platinum on both sides of the cantilever. This coating also enhances the laser reflectivity of the cantilever
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	190 kHz	+/- 60 kHz
Force Constant	48 N/m	20 - 100 N/m
Cantilever Length	225 μm	+/- 12 μm
Mean Width	38 μm	+/- 9 μm
Thickness	7 μm	+/- 1 μm
Tip Height	17 μm	+/- 2 μm
Tip Set Back	15 μm	+/- 5 μm
Tip Radius	< 25 nm	
Coating	Cr/Pt on both sides	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	
Contact Resistance	300 Ohms on platinum thin film surface	

Order Code	Units in Package	Coating	Price
Tap190E-G-10	10 pieces	Chrome / Platinum	\$240
Tap190E-G-50	50 pieces	Chrome / Platinum	\$1000